Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	F
10/677,439	MEDNIK ET AL.	
Examiner	Art Unit	-
Y. J. Han	2838	

SEARCHED				
Class	Subclass	Date	Examiner	
363	93			
	18			
	19			
	20			
	21.01			
	21.03			
	21.11	·		
	21.16			
	21.17			
	21.18			
323	266			
	285			
	284	5/05	9H	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
363	19			
	21.01			
	21.18	5/05	9R	
323/285		5/05	OR .	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
,	DATE	EXMR
	-	